

PATENT ABSTRACTS OF JAPAN

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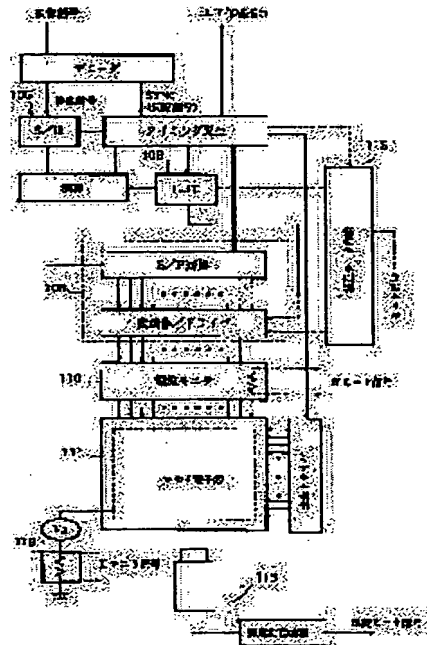
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(54) MULTIPLE ELECTRON BEAM SOURCE AND ITS DRIVING METHOD, AND IMAGE FORMING DEVICE USING THE SAME

(57) Abstract:

PURPOSE: To correct variance in luminance among respective surface conduction type emission(SCE) elements arranged on an image formation panel.
CONSTITUTION: An element current of each SCE element on the image formation panel when a signal having a certain value is inputted is monitored at a correction data generation part 113 by a current monitor 110. When the value does not match the stored element current data, the monitored element current is so connected as to match the stored current data. A proper value is written in a correction table in an LUT 106 for correcting the input signal so that the monitored element current is corrected so as to match the stored current data. Then, the element current of the element which is driven with the corrected signal is measured again and compared with the current data again. This processing is repeated until the monitored element current nearly matches the stored element current data. Thus, this processing is carried out as to all the elements to correct the variance. In this case, the luminance may be monitored by a luminance measuring instrument 115 or the discharge current from the SCE element may be monitored by a current monitor 118 instead of the element current.



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